

# IRFW830B / IRFI830B

## **500V N-Channel MOSFET**

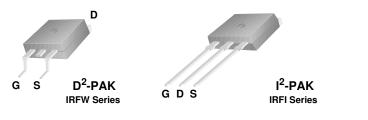
### **General Description**

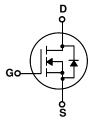
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies, power factor correction and electronic lamp ballasts based on half bridge.

#### **Features**

- 4.5A, 500V,  $R_{DS(on)} = 1.5\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 27 nC)
- · Low Crss (typical 17 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





# **Absolute Maximum Ratings** T<sub>C</sub> = 25°C unless otherwise noted

Symbol	ol Parameter		IRFW830B / IRFI830B	Units
V <sub>DSS</sub>	Drain-Source Voltage		500	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°C)	)	4.5	Α
	- Continuous (T <sub>C</sub> = 100°C	C)	2.9	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	18	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	270	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	4.5	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	7.3	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>A</sub> = 25°C) *		3.13	W
	Power Dissipation (T <sub>C</sub> = 25°C)		73	W
	- Derate above 25°C		0.58	W/°C
T <sub>J</sub> , T <sub>stg</sub>	Operating and Storage Temperature Rang	е	-55 to +150	°C
T <sub>L</sub>	Maximum lead temperature for soldering p 1/8" from case for 5 seconds	urposes,	300	°C

## **Thermal Characteristics**

Symbol	ymbol Parameter		Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.71	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

<sup>\*</sup> When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	\$	Min	Тур	Max	Units
Off Cha	aracteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		500			V
$\Delta BV_{DSS}$ / $\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced	l to 25°C		0.54		V/°C
I <sub>DSS</sub>	Zero Oeda Valla va Busia Oessaal	V <sub>DS</sub> = 500 V, V <sub>GS</sub> = 0 V				10	μΑ
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 400 V, T <sub>C</sub> = 125°C				100	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$		2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 2.25 A			1.16	1.5	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 40 \text{ V}, I_{D} = 2.25 \text{ A}$	(Note 4)		4.2		S
C <sub>iss</sub> C <sub>oss</sub>	Input Capacitance Output Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1.0 MHz			800 76	1050	pF pF
C <sub>rss</sub>	Reverse Transfer Capacitance	f = 1.0 MHZ			17	22	pF
	•						Ρ.
	ing Characteristics	1					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = 250 \text{ V}, I_D = 4.5 \text{ A},$			15	40	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$			40	90	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		(Note 4, 5)		85	180	ns
t <sub>f</sub>	Turn-Off Fall Time		(**************************************		45	100	ns
Q <sub>g</sub>	Total Gate Charge	$V_{DS} = 400 \text{ V}, I_D = 4.5 \text{ A},$			27	35	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V	(Note 4, 5)		4.0		nC
Q <sub>gd</sub>	Gate-Drain Charge		(14010 4, 0)		12		nC
Drain-S	Source Diode Characteristics at	nd Maximum Rating	s				
I <sub>S</sub>	Maximum Continuous Drain-Source Did	<u> </u>				4.5	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F	orward Current				18	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 4.5 \text{ A}$				1.4	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 4.5 \text{ A},$			305		ns
Q <sub>rr</sub>	Reverse Recovery Charge	dl <sub>F</sub> / dt = 100 A/μs	(Note 4)		2.6		μС

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 24mH,  $I_{AS}$  = 4.5A,  $V_{DD}$  = 50V,  $R_{G}$  = 25 Ω, Starting  $T_{J}$  = 25°C 3.  $I_{SD}$  ≤ 4.5A, di/dt ≤ 300A/μs,  $V_{DD}$  ≤ BV<sub>DSS</sub>, Starting  $T_{J}$  = 25°C 4. Pulse Test : Pulse width ≤ 300 $\mu$ s, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

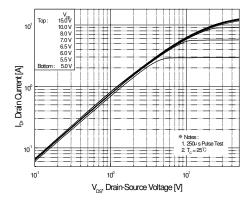


Figure 1. On-Region Characteristics

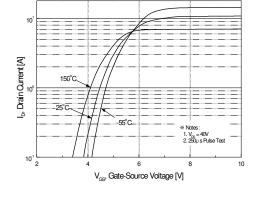


Figure 2. Transfer Characteristics

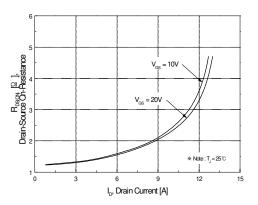


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

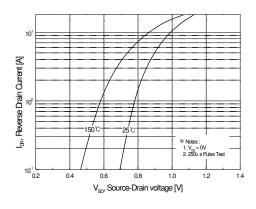


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

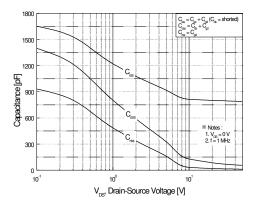


Figure 5. Capacitance Characteristics

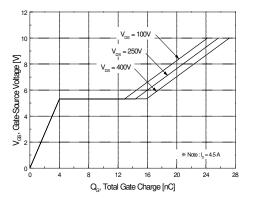


Figure 6. Gate Charge Characteristics

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# Typical Characteristics (Continued)

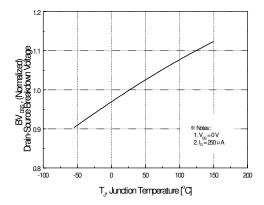


Figure 7. Breakdown Voltage Variation vs Temperature

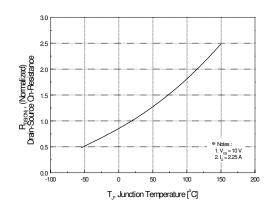


Figure 8. On-Resistance Variation vs Temperature

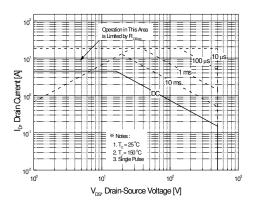


Figure 9. Maximum Safe Operating Area

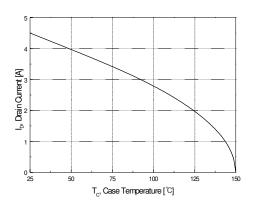


Figure 10. Maximum Drain Current vs Case Temperature

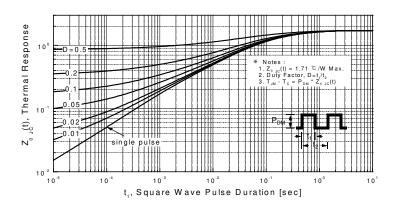
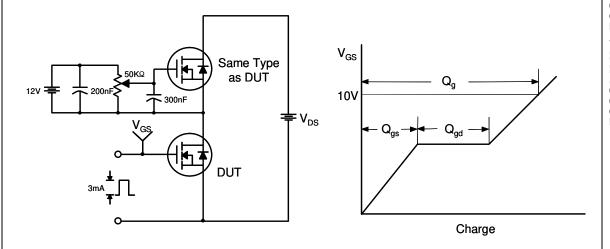


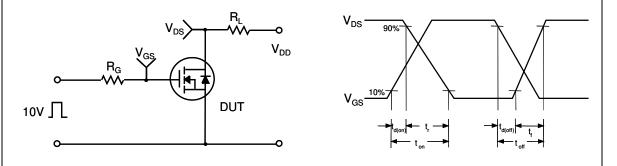
Figure 11. Transient Thermal Response Curve

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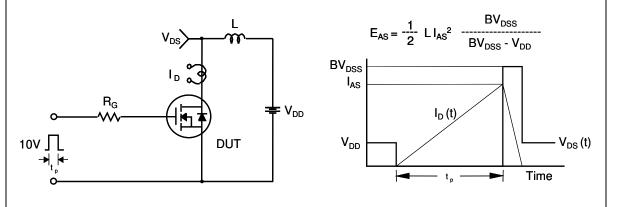
## **Gate Charge Test Circuit & Waveform**



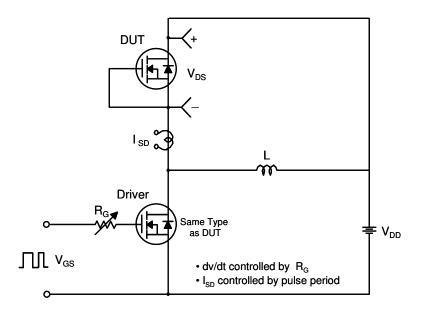
## **Resistive Switching Test Circuit & Waveforms**

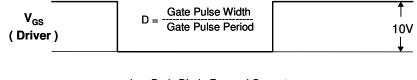


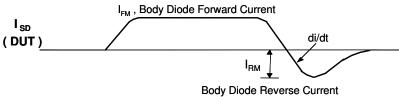
## **Unclamped Inductive Switching Test Circuit & Waveforms**

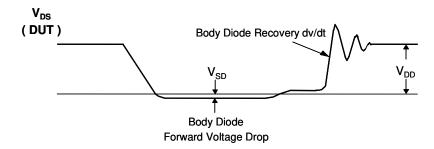


## Peak Diode Recovery dv/dt Test Circuit & Waveforms

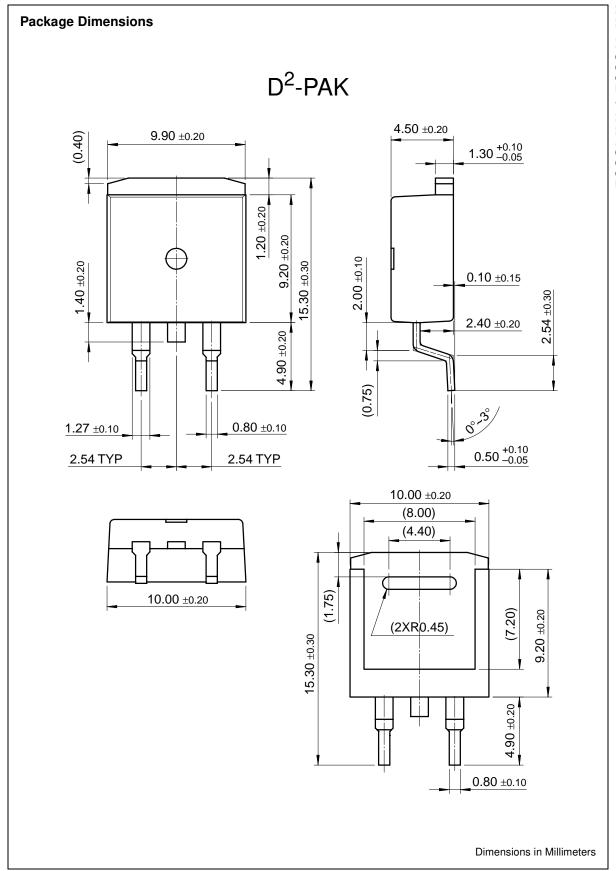


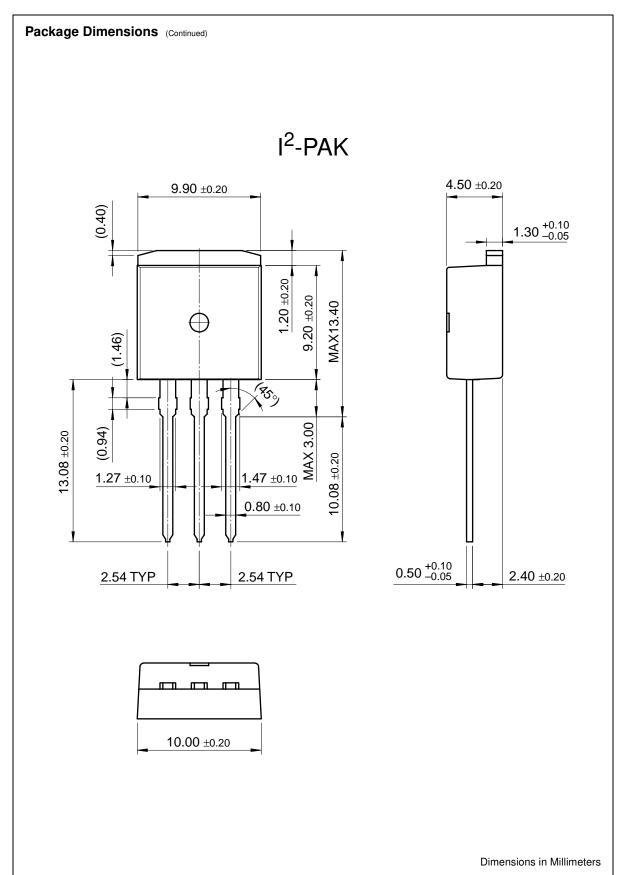






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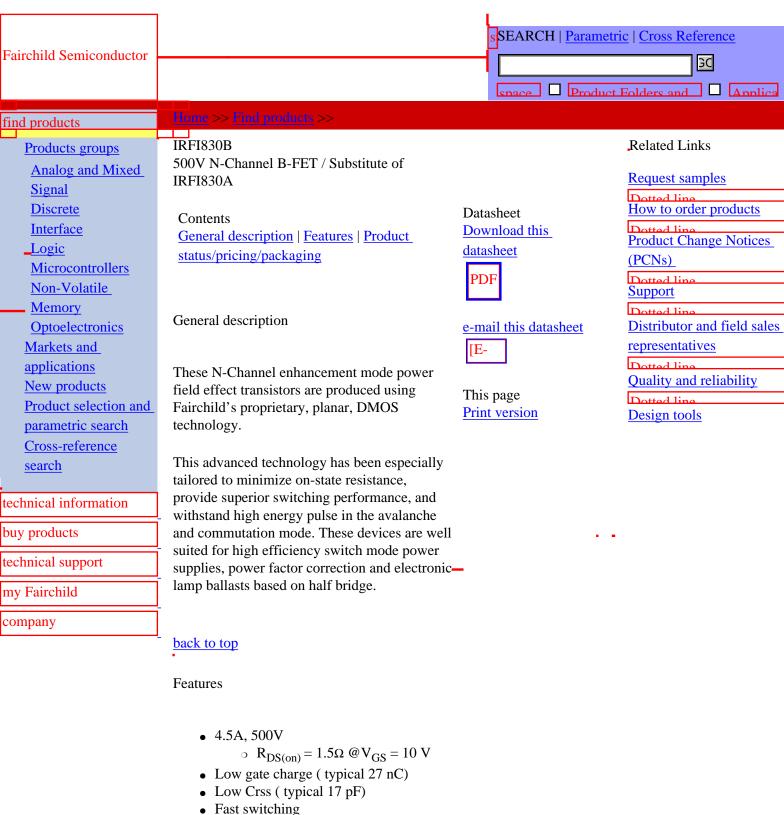
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- 100% avalanche tested
- Improved dv/dt capability

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Product status/pricing/packaging

Product	Product status	Pricing*	Package type	Leads	Packing method	

Product Folder - Fairchild P/N IRFI830B - 500V N-Channel B-FET / Substitute of IRFI830A

IRFI830BTU	Full Production	\$0.79	TO-262(I2PAK)	3	RAIL

<sup>\* 1,000</sup> piece Budgetary Pricing

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